

TS3A5017 デュアルSP4Tアナログ・スイッチ/マルチプレクサ/デマルチプレクサ

1 特長

- パワーダウン・モードでの絶縁、 $V_+ = 0$
- 低いオン抵抗
- 低い電荷注入
- 非常に優れたオン抵抗マッチング
- 低い全高調波歪(THD)
- 2.3V~3.6Vの単電源で動作
- JESD 78, Class II準拠で100mA超のラッチアップ性能
- ESD性能はJESD 22に準拠しテスト済み
 - 人体モデルで1500V(A114-B, Class II)
 - 荷電デバイス・モデルで1000V (C101)

2 アプリケーション

- サンプル・アンド・ホールド回路
- バッテリ駆動の機器
- オーディオおよびビデオ信号のルーティング
- 通信用回路

3 概要

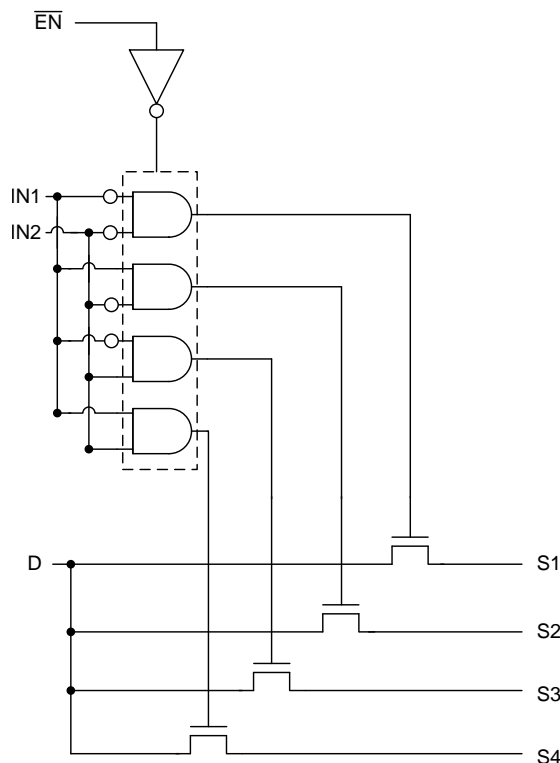
TS3A5017デバイスはデュアル単極4投(4:1)アナログ・スイッチで、2.3V~3.6Vで動作するように設計されています。このデバイスはデジタルとアナログの両方の信号を処理でき、 V_+ までの信号をどちらの方向にも転送できます。

製品情報⁽¹⁾

型番	パッケージ	本体サイズ(公称)
TS3A5017	SOIC (16)	9.90mm×3.90mm
	SSOP (16)	4.90mm×3.90mm
	TSSOP (16)	5.00mm×4.40mm
	TVSOP (16)	4.40mm×3.60mm
	UQFN (16)	2.50mm×1.80mm
	VQFN (16)	4.00mm×3.50mm

(1) 提供されているすべてのパッケージについては、データシートの末尾にある注文情報を参照してください。

ブロック図



目次

1	特長	1	8.2	Functional Block Diagram	14
2	アプリケーション	1	8.3	Feature Description	14
3	概要	1	8.4	Device Functional Modes	15
4	改訂履歴	2	9	Application and Implementation	16
5	Pin Configuration and Functions	3	9.1	Application Information	16
6	Specifications	4	9.2	Typical Application	16
6.1	Absolute Maximum Ratings	4	10	Power Supply Recommendations	17
6.2	ESD Ratings	4	11	Layout	17
6.3	Recommended Operating Conditions	4	11.1	Layout Guidelines	17
6.4	Thermal Information	4	11.2	Layout Example	18
6.5	Electrical Characteristics for 3.3-V Supply	5	12	デバイスおよびドキュメントのサポート	19
6.6	Electrical Characteristics for 2.5-V Supply	6	12.1	デバイス・サポート	19
6.7	Switching Characteristics for 3.3-V supply	7	12.2	ドキュメントのサポート	19
6.8	Switching Characteristics for 2.5-V supply	7	12.3	商標	20
6.9	Typical Characteristics	8	12.4	静電気放電に関する注意事項	20
7	Parameter Measurement Information	10	12.5	Glossary	20
8	Detailed Description	14	13	メカニカル、パッケージ、および注文情報	21
8.1	Overview	14			

4 改訂履歴

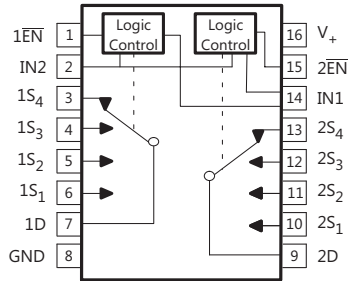
Revision F (October 2018) から Revision G に変更		Page
• 「特長」の「人体モデルで2000V」を「人体モデルで1500V」に変更	1
• Changed the HBM value From: ± 2000 V To: ± 1500 V in the <i>ESD Ratings</i>	4

Revision E (April 2015) から Revision F に変更		Page
• Changed the X_{TALK} MAX value From: -49 dB To -69 dB in the <i>Electrical Characteristics for 3.3-V Supply</i>	6

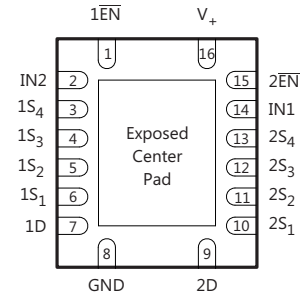
Revision D (December 2008) から Revision E に変更		Page
• 「アプリケーション」セクション、「製品情報」表、「ピン機能」表、「ESD定格」表、「熱に関する情報」表、「代表的特性」セクション、「機能説明」セクション、「デバイスの機能モード」セクション、「アプリケーションと実装」セクション、「電源に関する推奨事項」セクション、「レイアウト」セクション、「デバイスおよびドキュメントのサポート」セクション、「メカニカル、パッケージ、および注文情報」セクションを追加	1
• 「注文情報」表を削除	1

5 Pin Configuration and Functions

**D, DBQ, DGV, and PW Package
16-Pin SOIC, SSOP, TVSOP and TSSOP
(Top View)**

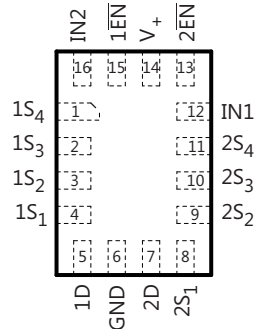


**RGY Package
16-Pin VQFN
(Top View)**



If exposed center pad is used, it must be connected as a secondary ground or left electrically open.

**RSV Package
16-Pin UQFN
(Top View)**



Pin Functions

NAME	PIN		TYPE	DESCRIPTION
	SOIC, SSOP, TVSOP, TSSOP, VQFN NO.	UQFN NO.		
1D	7	5	I/O	Common path for switch 1
1EN	1	15	I	Active-low enable for switch 1
1S1	6	4	I/O	Switch 1 channel 1
1S2	5	3	I/O	Switch 1 channel 2
1S3	4	2	I/O	Switch 1 channel 3
1S4	3	1	I/O	Switch 1 channel 4
2D	9	7	I/O	Common path for switch 2
2EN	15	13	I	Active-low enable for switch 2
2S1	10	8	I/O	Switch 2 channel 1
2S2	11	9	I/O	Switch 2 channel 2
2S3	12	10	I/O	Switch 2 channel 3
2S4	13	11	I/O	Switch 2 channel 4
GND	8	6	–	Ground
IN1	14	12	I	Switch 1 input select
IN2	2	16	I	Switch 2 input select
V+	16	14	–	Supply voltage

6 Specifications

6.1 Absolute Maximum Ratings

 over operating free-air temperature range (unless otherwise noted)⁽¹⁾⁽²⁾

		MIN	MAX	UNIT
V_+	Supply voltage ⁽³⁾	-0.5	4.6	V
V_S, V_D	Analog voltage ⁽³⁾⁽⁴⁾	-0.5	4.6	V
I_{SK}, I_{DK}	Analog port clamp current	$V_S, V_D < 0$		mA
I_S, I_D	ON-state switch current	$V_S, V_D = 0$ to 7 V		mA
V_I	Digital input voltage	-0.5	4.6	V
I_{IK}	Digital input clamp current ⁽³⁾⁽⁴⁾	$V_I < 0$		mA
I_+	Continuous current through V_+		100	mA
I_{GND}	Continuous current through GND	-100		mA
T_{stg}	Storage temperature	-65	150	°C

- (1) Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under *Recommended Operating Conditions* is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.
- (2) The algebraic convention, whereby the most negative value is a minimum and the most positive value is a maximum.
- (3) All voltages are with respect to ground, unless otherwise specified.
- (4) The input and output voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

6.2 ESD Ratings

		VALUE	UNIT
$V_{(ESD)}$	Electrostatic discharge	Human-body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	V
		Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾	

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.

6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	MAX	UNIT
$V_{I/O}$	Switch input/output voltage range	0	3.6	V
V_+	Supply voltage range	2.3	3.6	V
V_I	Control input voltage range	0	3.6	V
T_A	Operating Temperature Range	-40	85	°C

6.4 Thermal Information

THERMAL METRIC ⁽¹⁾	TS3A5018						UNIT	
	D (SOIC)	DBQ (SSOP)	DGV (TVSOP)	PW (TSSOP)	RGY (VQFN)	RSV (UQFN)		
	16 PINS	16 PINS	16 PINS	16 PINS	16 PINS	16 PINS		
$R_{\theta JA}$	Junction-to-ambient thermal resistance	73	82	120	108	91.6	184	°C/W

- (1) For more information about traditional and new thermal metrics, see the *IC Package Thermal Metrics* application report, [SPRA953](#).

6.5 Electrical Characteristics for 3.3-V Supply

 $V_+ = 2.7\text{ V to }3.6\text{ V}$, $T_A = -40^\circ\text{C to }85^\circ\text{C}$ (unless otherwise noted)⁽¹⁾

PARAMETER		TEST CONDITIONS		T_A	V_+	MIN	TYP	MAX	UNIT
Analog Switch									
V_D, V_S	Analog signal range					0		V_+	V
r_{on}	ON-state resistance	$0 \leq V_S \leq V_+$, $I_D = -32\text{ mA}$,	Switch ON, see Figure 12	25°C	3 V		11	12	Ω
				Full			14		
Δr_{on}	ON-state resistance match between channels	$V_S = 2.1\text{ V}$, $I_D = -32\text{ mA}$,	Switch ON, see Figure 12	25°C	3 V		1	2	Ω
				Full			3		
$r_{on(Flat)}$	ON-state resistance flatness	$0 \leq V_S \leq V_+$, $I_D = -32\text{ mA}$,	Switch ON, see Figure 12	25°C	3 V		7	9	Ω
				Full			10		
$I_{S(OFF)}$	S OFF leakage current	$V_S = 1\text{ V}, V_D = 3\text{ V}$, or $V_S = 3\text{ V}, V_D = 1\text{ V}$,	Switch OFF, see Figure 13	25°C	3.6 V	-0.1	0.05	0.1	μA
				Full		-0.2		0.2	
$I_{SPWR(OFF)}$		$V_S = 0\text{ to }3.6\text{ V}$, $V_D = 3.6\text{ V to }0$,		25°C	0 V	-1	0.5	1	μA
				Full		-5		5	
$I_{D(OFF)}$	D OFF leakage current	$V_S = 1\text{ V}, V_D = 3\text{ V}$, or $V_S = 3\text{ V}, V_D = 1\text{ V}$,	Switch OFF, see Figure 13	25°C	3.6 V	-0.1	0.05	0.1	μA
				Full		-0.2		0.2	
$I_{DPWR(OFF)}$		$V_D = 0\text{ to }3.6\text{ V}$, $V_S = 3.6\text{ V to }0$,		25°C	0 V	-1	0.5	1	μA
				Full		-5		5	
$I_{S(ON)}$	S ON leakage current	$V_S = 1\text{ V}, V_D = \text{Open}$, or $V_S = 3\text{ V}, V_D = \text{Open}$,	Switch ON, see Figure 14	25°C	3.6 V	-0.1	0.05	0.1	μA
				Full		-0.2		0.2	
$I_{D(ON)}$	D ON leakage current	$V_D = 1\text{ V}, V_S = \text{Open}$, or $V_D = 3\text{ V}, V_S = \text{Open}$,	Switch ON, see Figure 14	25°C	3.6 V	-0.1	0.05	0.1	μA
				Full		-0.2		0.2	
Digital Control Inputs (IN1, IN2, EN)⁽²⁾									
V_{IH}	Input logic high			Full		2		V_+	V
V_{IL}	Input logic low			Full		0		0.8	V
I_{IH}, I_{IL}	Input leakage current	$V_I = V_+$ or 0		25°C	3.6 V	-1	0.05	1	μA
				Full		-1		1	
Q_C	Charge injection	$V_{GEN} = 0, R_{GEN} = 0$, $C_L = 0.1\text{ nF}$,	See Figure 21	25°C	3.3 V		5		pC
$C_{S(OFF)}$	S OFF capacitance	$V_S = V_+$ or GND, Switch OFF,	See Figure 15	25°C	3.3 V		4.5		pF
$C_{D(OFF)}$	D OFF capacitance	$V_D = V_+$ or GND, Switch OFF,	See Figure 15	25°C	3.3 V		19		pF
$C_{S(ON)}$	S ON capacitance	$V_S = V_+$ or GND, Switch ON,	See Figure 15	25°C	3.3 V		25		pF
$C_{D(ON)}$	D ON capacitance	$V_D = V_+$ or GND, Switch ON,	See Figure 15	25°C	3.3 V		25		pF
C_I	Digital input capacitance	$V_I = V_+$ or GND,	See Figure 15	25°C	3.3 V		2		pF
BW	Bandwidth	$R_L = 50\ \Omega$, Switch ON,	See Figure 17	25°C	3.3 V		165		MHz
O_{ISO}	OFF isolation	$R_L = 50\ \Omega$, $f = 1\text{ MHz}$,	See Figure 18	25°C	3.3 V		-69		dB

(1) The algebraic convention, whereby the most negative value is a minimum and the most positive value is a maximum

(2) All unused digital inputs of the device must be held at V_+ or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

Electrical Characteristics for 3.3-V Supply (continued)
 $V_+ = 2.7 \text{ V to } 3.6 \text{ V}$, $T_A = -40^\circ\text{C to } 85^\circ\text{C}$ (unless otherwise noted)⁽¹⁾

PARAMETER		TEST CONDITIONS		T_A	V_+	MIN	TYP	MAX	UNIT
X_{TALK}	Crosstalk	$R_L = 50 \Omega$, $f = 1 \text{ MHz}$,	See Figure 19	25°C	3.3 V		-69		dB
$X_{\text{TALK(ADJ)}}$	Crosstalk adjacent	$R_L = 50 \Omega$, $f = 1 \text{ MHz}$,	See Figure 20	25°C	3.3 V		-74		dB
THD	Total harmonic distortion	$R_L = 600 \Omega$, $C_L = 50 \text{ pF}$,	$f = 20 \text{ Hz to } 20 \text{ kHz}$, see Figure 22	25°C	3.3 V		0.21%		
Supply									
I_+	Positive supply current	$V_I = V_+$ or GND,	Switch ON or OFF	25°C	3.6 V		2.5	7	μA
				Full				10	

6.6 Electrical Characteristics for 2.5-V Supply
 $V_+ = 2.3 \text{ V to } 2.7 \text{ V}$, $T_A = -40^\circ\text{C to } 85^\circ\text{C}$ (unless otherwise noted)⁽¹⁾

PARAMETER		TEST CONDITIONS		T_A	V_+	MIN	TYP	MAX	UNIT
Analog Switch									
V_D, V_S	Analog signal range					0		V_+	V
r_{on}	ON-state resistance	$0 \leq V_S \leq V_+$, $I_D = -24 \text{ mA}$,	Switch ON, see Figure 12	25°C	2.3 V		20.5	22	Ω
				Full				24	
Δr_{on}	ON-state resistance match between channels	$V_S = 1.6 \text{ V}$, $I_D = -24 \text{ mA}$,	Switch ON, see Figure 12	25°C	2.3 V		1	2	Ω
				Full				3	
$r_{\text{on(flat)}}$	ON-state resistance flatness	$0 \leq V_S \leq V_+$, $I_D = -24 \text{ mA}$,	Switch ON, see Figure 12	25°C	2.3 V		16	18	Ω
				Full				20	
$I_{\text{S(OFF)}}$	S OFF leakage current	$V_S = 0.5 \text{ V}$, $V_D = 2.2 \text{ V}$, or $V_S = 2.2 \text{ V}$, $V_D = 0.5 \text{ V}$,	Switch OFF, see Figure 13	25°C	2.7 V	-0.1	0.05	0.1	μA
$I_{\text{SPWR(OFF)}}$		$V_S = 0$ to 2.7 V , $V_D = 2.7 \text{ V to } 0$,		Full		0 V	-0.2		
$I_{\text{D(OFF)}}$	D OFF leakage current	$V_S = 0.5 \text{ V}$, $V_D = 2.2 \text{ V}$, or $V_S = 2.2 \text{ V}$, $V_D = 0.5 \text{ V}$,	Switch OFF, see Figure 13	25°C	2.7 V	-0.1	0.05	0.1	μA
$I_{\text{DPWR(OFF)}}$		$V_D = 0$ to 2.7 V , $V_S = 2.7 \text{ V to } 0$,		Full		0 V	-0.2		
$I_{\text{S(ON)}}$	S ON leakage current	$V_S = 0.5 \text{ V}$, $V_D = \text{Open}$, or $V_S = 2.2 \text{ V}$, $V_D = \text{Open}$,	Switch ON, see Figure 14	25°C	2.7 V	-0.1	0.05	0.1	μA
$I_{\text{D(ON)}}$	D ON leakage current	$V_D = 0.5 \text{ V}$, $V_S = \text{Open}$, or $V_D = 2.2 \text{ V}$, $V_S = \text{Open}$,	Switch ON, see Figure 14	Full		2.7 V	-0.2		
Digital Control Inputs (IN1, IN2, EN)⁽²⁾									
V_{IH}	Input logic high			Full		1.7		V_+	V
V_{IL}	Input logic low			Full		0		0.7	V
$I_{\text{IH}}, I_{\text{IL}}$	Input leakage current	$V_I = V_+$ or 0		25°C	2.7 V	-1	0.05	1	μA
				Full				-1	
Q_C	Charge injection	$V_{\text{GEN}} = 0$, $R_{\text{GEN}} = 0$, $C_L = 0.1 \text{ nF}$,	See Figure 21	25°C	2.5 V				pC
$C_{\text{S(OFF)}}$	S OFF capacitance	$V_S = V_+$ or GND, Switch OFF,	See Figure 15	25°C	2.5 V		4.5		pF

(1) The algebraic convention, whereby the most negative value is a minimum and the most positive value is a maximum

(2) All unused digital inputs of the device must be held at V_+ or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.

Electrical Characteristics for 2.5-V Supply (continued)
 $V_+ = 2.3 \text{ V to } 2.7 \text{ V}$, $T_A = -40^\circ\text{C to } 85^\circ\text{C}$ (unless otherwise noted)⁽¹⁾

PARAMETER		TEST CONDITIONS		T_A	V_+	MIN	TYP	MAX	UNIT
$C_{D(OFF)}$	D OFF capacitance	$V_D = V_+$ or GND, Switch OFF,	See Figure 15	25°C	2.5 V		18.5		pF
$C_{S(ON)}$	S ON capacitance	$V_S = V_+$ or GND, Switch ON,	See Figure 15	25°C	2.5 V		24		pF
$C_{D(ON)}$	D ON capacitance	$V_D = V_+$ or GND, Switch ON,	See Figure 15	25°C	2.5 V		24		pF
C_I	Digital input capacitance	$V_I = V_+$ or GND,	See Figure 15	25°C	2.5 V		2		pF
BW	Bandwidth	$R_L = 50 \Omega$, Switch ON,	See Figure 17	25°C	2.5 V		165		MHz
O_{ISO}	OFF isolation	$R_L = 50 \Omega$, $f = 1 \text{ MHz}$,	See Figure 18	25°C	2.5 V		-69		dB
X_{TALK}	Crosstalk	$R_L = 50 \Omega$, $f = 1 \text{ MHz}$,	See Figure 19	25°C	2.5 V		-69		dB
$X_{TALK(ADJ)}$	Crosstalk adjacent	$R_L = 50 \Omega$, $f = 1 \text{ MHz}$,	See Figure 20	25°C	2.5 V		-74		dB
THD	Total harmonic distortion	$R_L = 600 \Omega$, $C_L = 50 \text{ pF}$,	$f = 20 \text{ Hz to } 20 \text{ kHz}$, see Figure 22	25°C	2.5 V		0.29%		
Supply									
I_+	Positive supply current	$V_I = V_+$ or GND,	Switch ON or OFF	25°C	2.7 V		2.5	7	μA
				Full				10	

6.7 Switching Characteristics for 3.3-V supply

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		T_A	V_+	MIN	TYP	MAX	UNIT
t_{ON}	Turnon time	$V_D = 2 \text{ V}$, $R_L = 300 \Omega$,	$C_L = 35 \text{ pF}$, see Figure 16	25°C	3.3 V	1	5	9.5	ns
				Full	3 V to 3.6 V	1		10.5	
t_{OFF}	Turnoff time	$V_D = 2 \text{ V}$, $R_L = 300 \Omega$,	$C_L = 35 \text{ pF}$, see Figure 16	25°C	3.3 V	0.5	1.5	3.5	ns
				Full	3 V to 3.6 V	0.5		4.5	

6.8 Switching Characteristics for 2.5-V supply

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		T_A	V_+	MIN	TYP	MAX	UNIT
t_{ON}	Turnon time	$V_{COM} = 2 \text{ V}$, $R_L = 300 \Omega$,	$C_L = 35 \text{ pF}$, see Figure 16	25°C	2.5 V	1.5	5	8	ns
				Full	2.3 V to 2.7 V	1		10	
t_{OFF}	Turnoff time	$V_{COM} = 2 \text{ V}$, $R_L = 300 \Omega$,	$C_L = 35 \text{ pF}$, see Figure 16	25°C	2.5 V	0.3	2	4.5	ns
				Full	2.3 V to 2.7 V	0.3		6	

6.9 Typical Characteristics

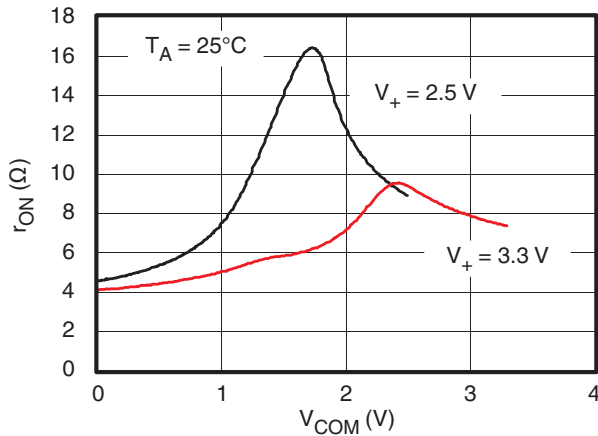


Figure 1. r_{on} vs V_{COM}

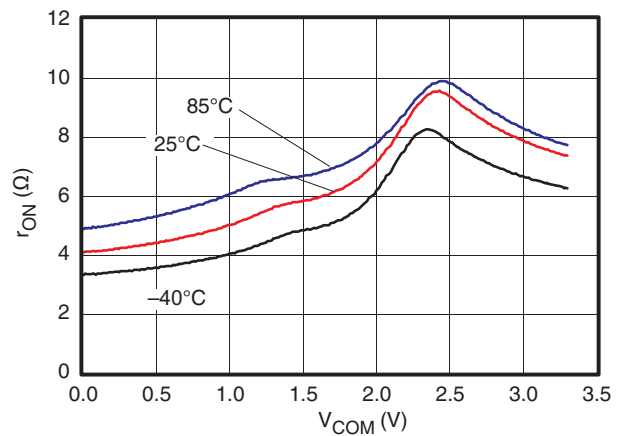


Figure 2. r_{on} vs V_{COM} ($V_+ = 3.3$ V)

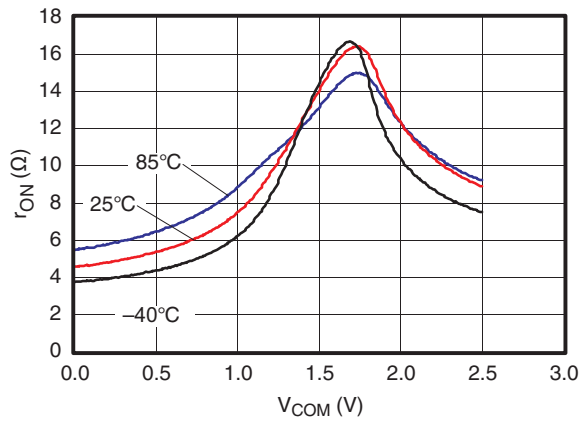


Figure 3. r_{on} vs V_{COM} ($V_+ = 2.5$ V)

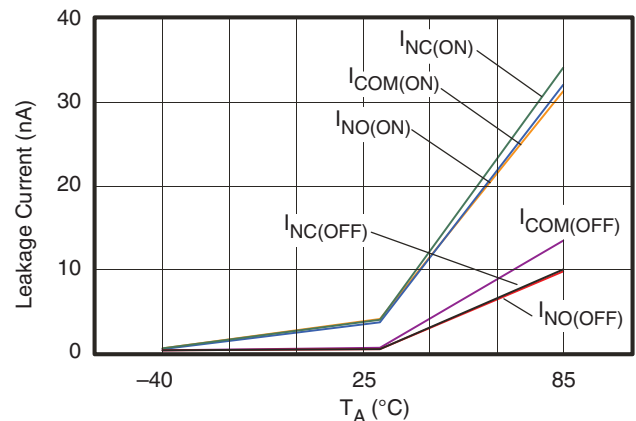


Figure 4. Leakage Current vs Temperature ($V_+ = 3.6$ V)

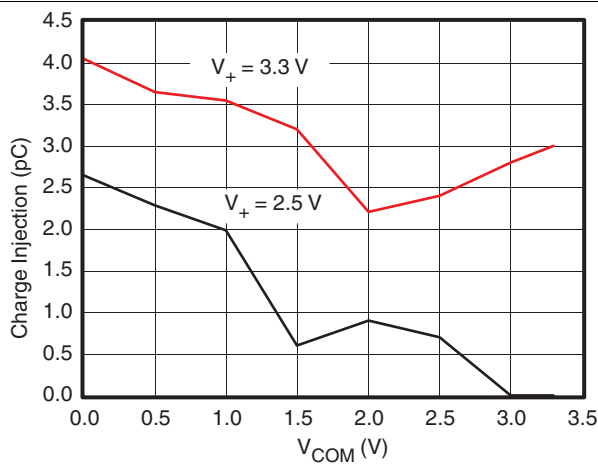


Figure 5. Charge Injection (Q_C) vs V_{COM}

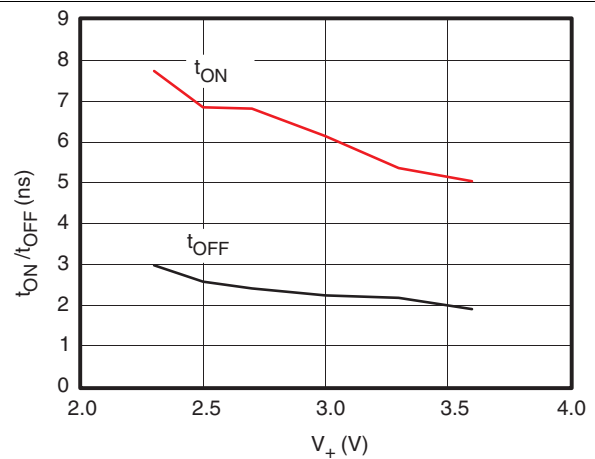


Figure 6. t_{ON} and t_{OFF} vs Supply Voltage

Typical Characteristics (continued)

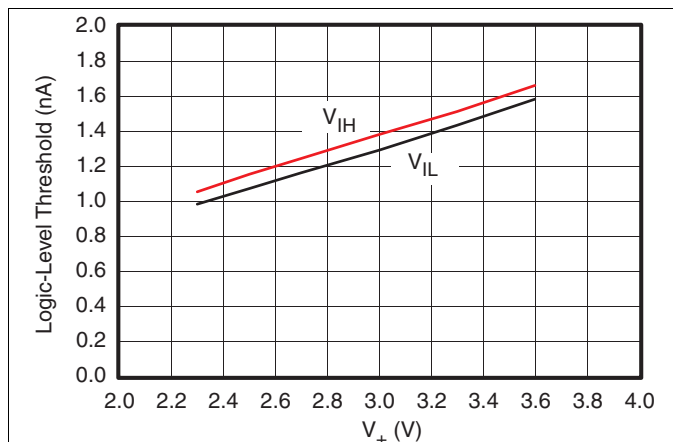


Figure 7. Logic-Level Threshold vs V_+

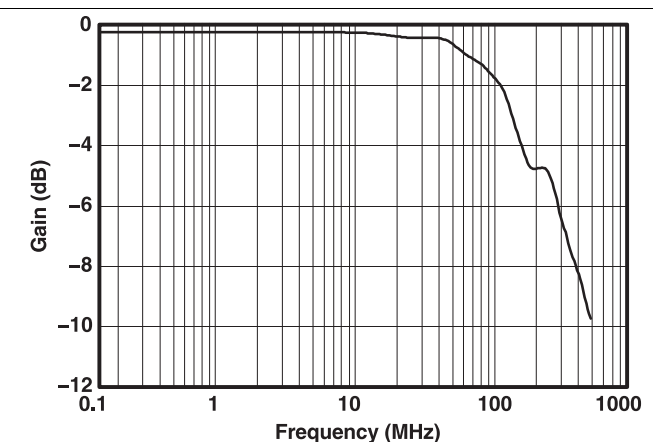


Figure 8. Bandwidth (Gain vs Frequency) ($V_+ = 3.3$ V)

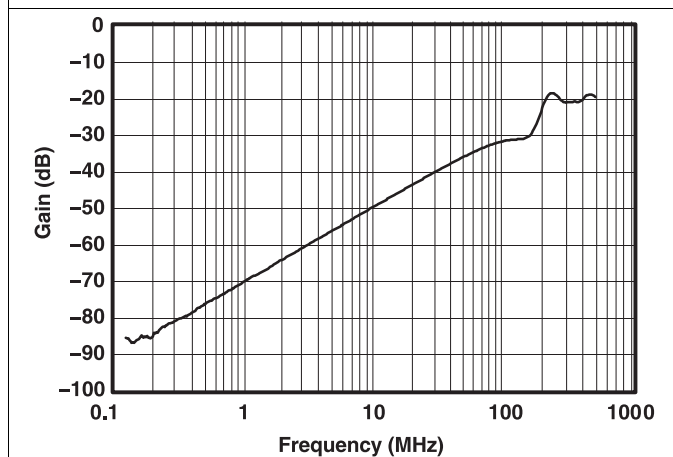


Figure 9. OFF Isolation and Crosstalk vs Frequency ($V_+ = 3.3$ V)

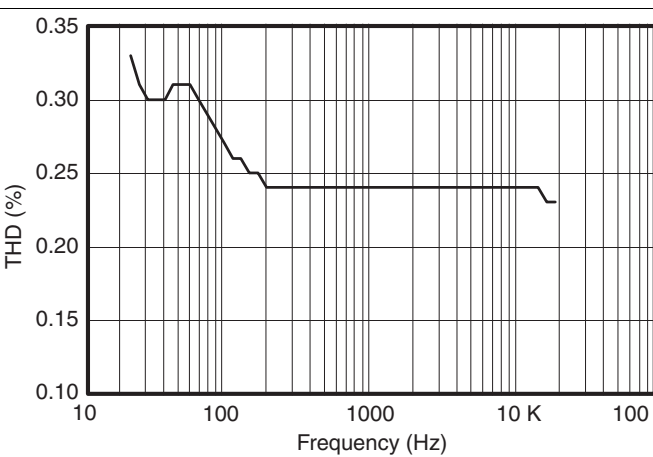


Figure 10. Total Harmonic Distortion vs Frequency

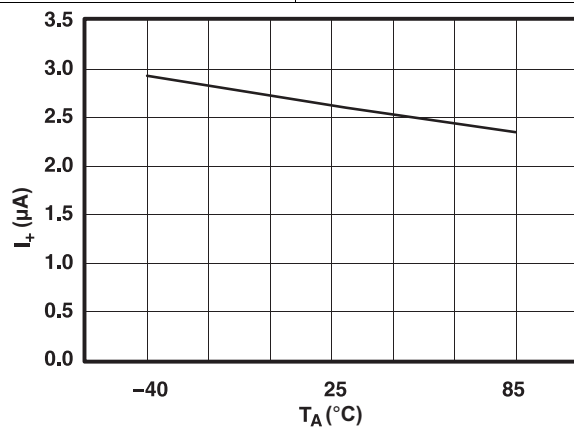


Figure 11. Power-Supply Current vs Temperature ($V_+ = 3.6$ V)

7 Parameter Measurement Information

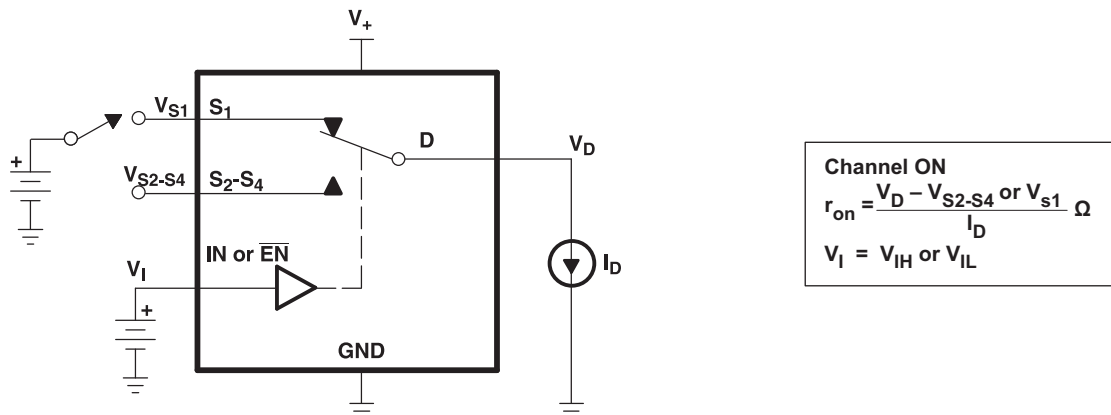


Figure 12. ON-State Resistance (r_{on})

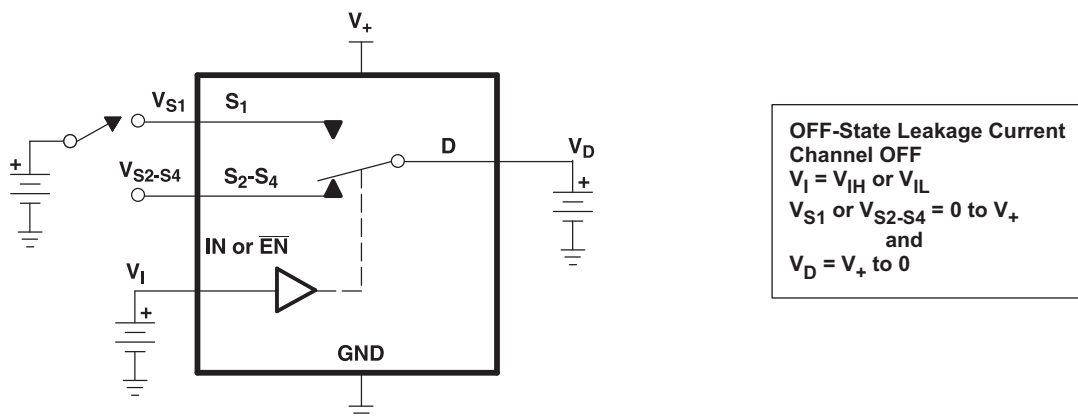


Figure 13. OFF-State Leakage Current ($I_{D(OFF)}$, $I_{S(OFF)}$)

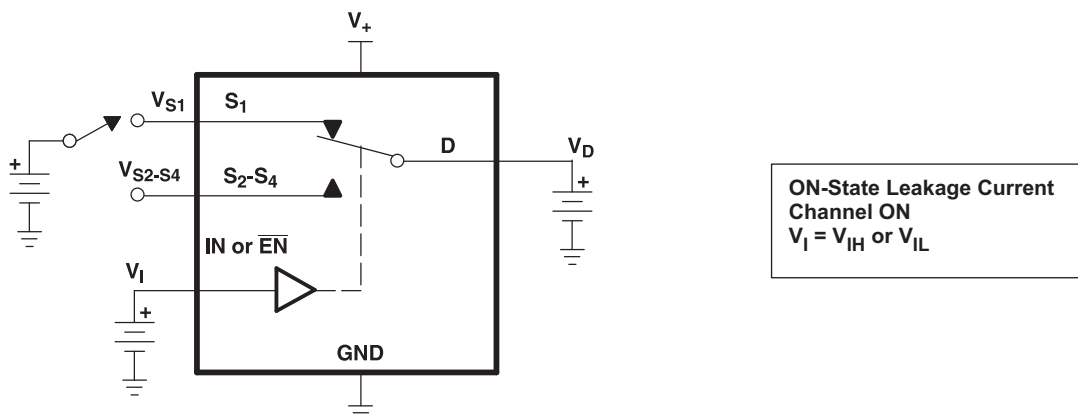


Figure 14. ON-State Leakage Current ($I_{D(ON)}$, $I_{S(ON)}$)

Parameter Measurement Information (continued)

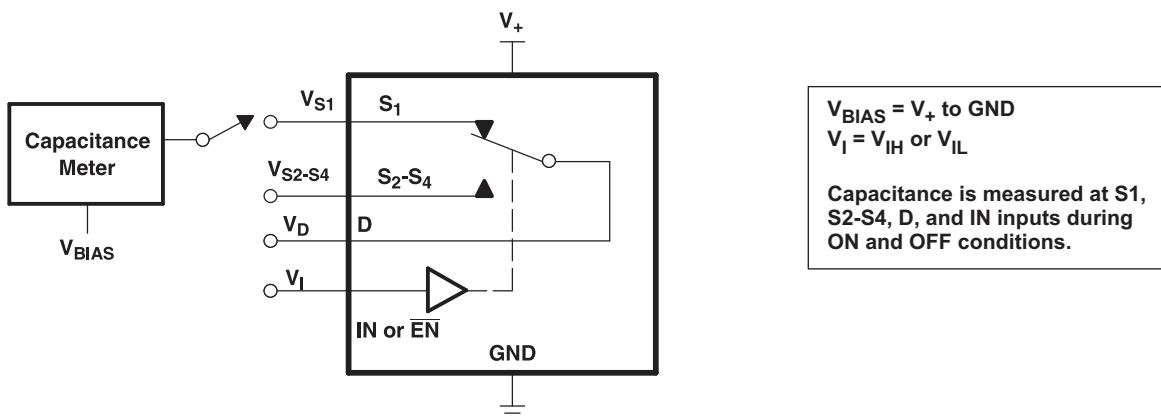
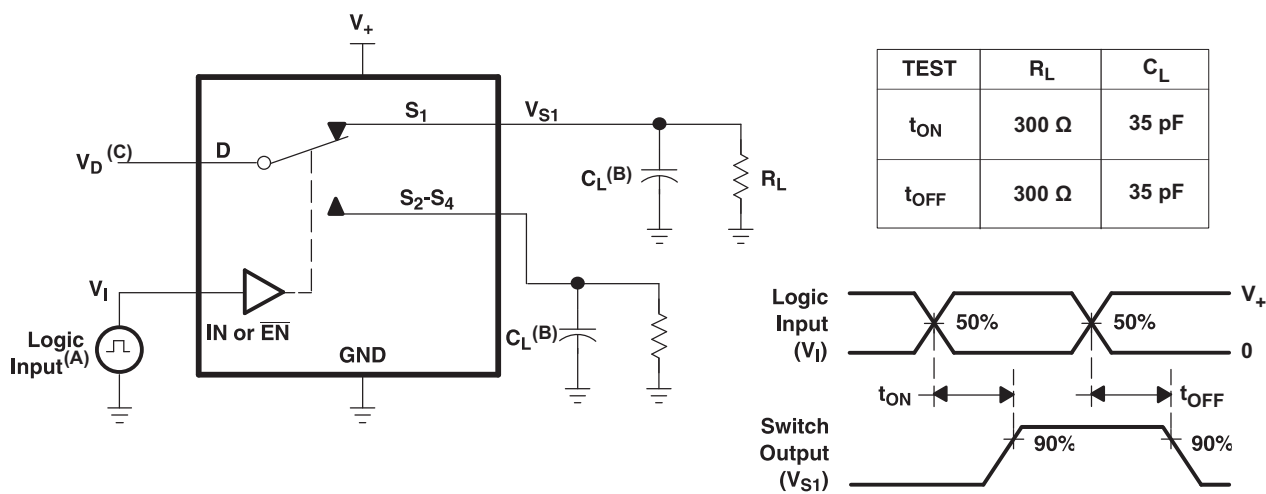


Figure 15. Capacitance (C_I , $C_{D(OFF)}$, $C_{D(ON)}$, $C_{S(OFF)}$, $C_{S(ON)}$)



- A. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \Omega$, $t_r < 5 \text{ ns}$, $t_f < 5 \text{ ns}$.
- B. C_L includes probe and jig capacitance.
- C. See Electrical Characteristics for V_D .

Figure 16. Turnon (t_{ON}) and Turnoff Time (t_{OFF})

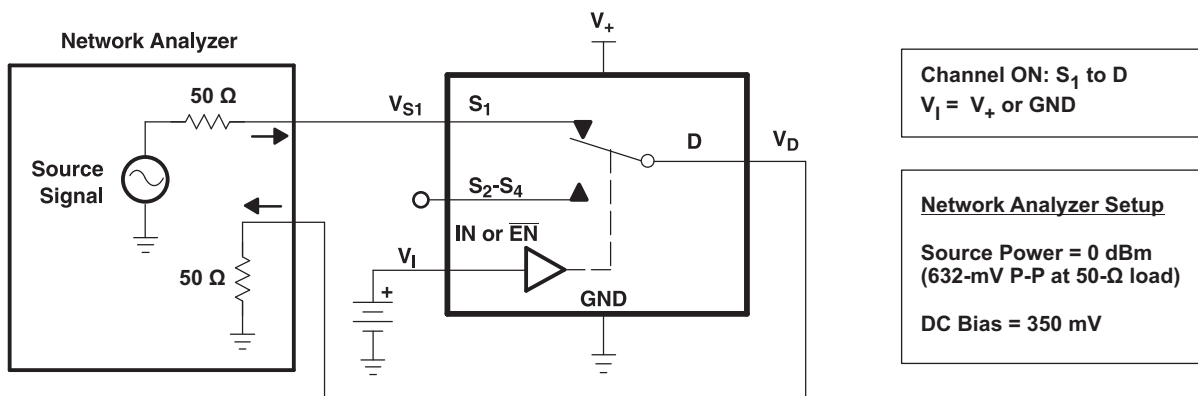


Figure 17. Bandwidth (BW)

Parameter Measurement Information (continued)

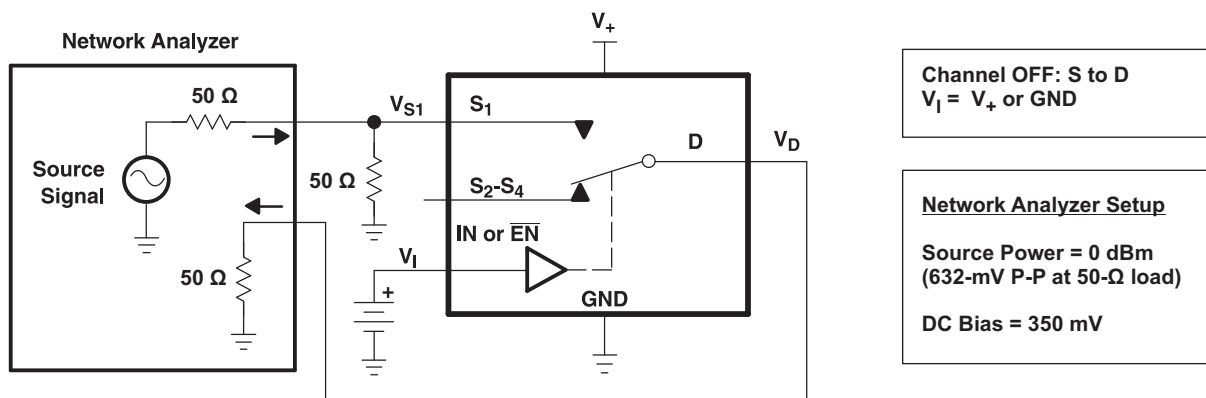


Figure 18. OFF Isolation (O_{ISO})

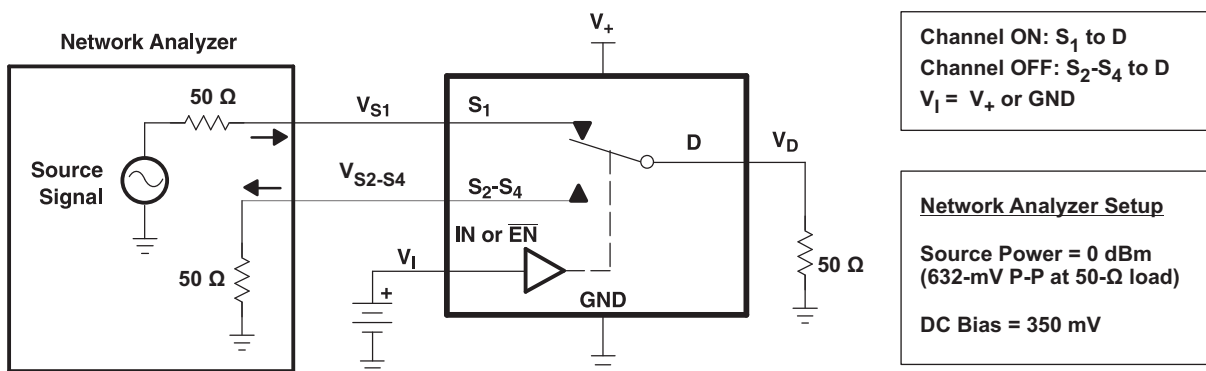


Figure 19. Crosstalk (X_{TALK})

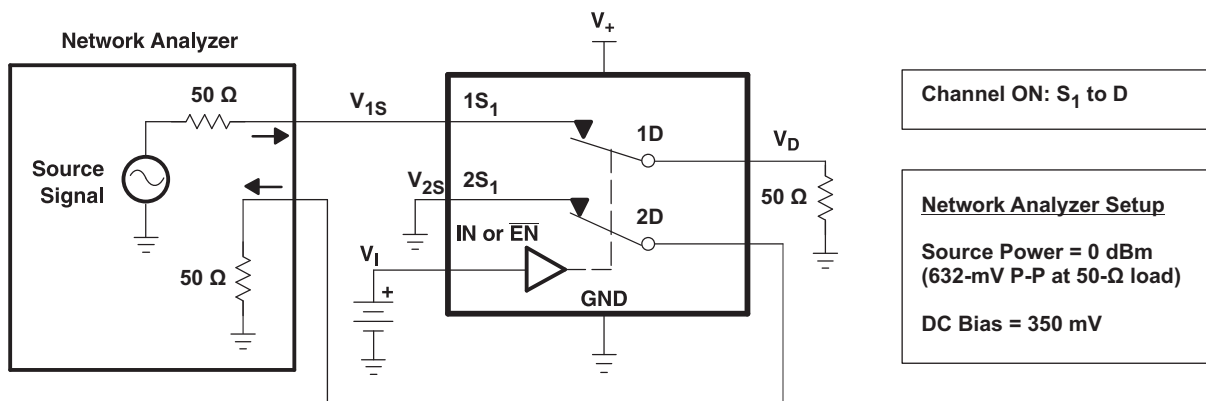
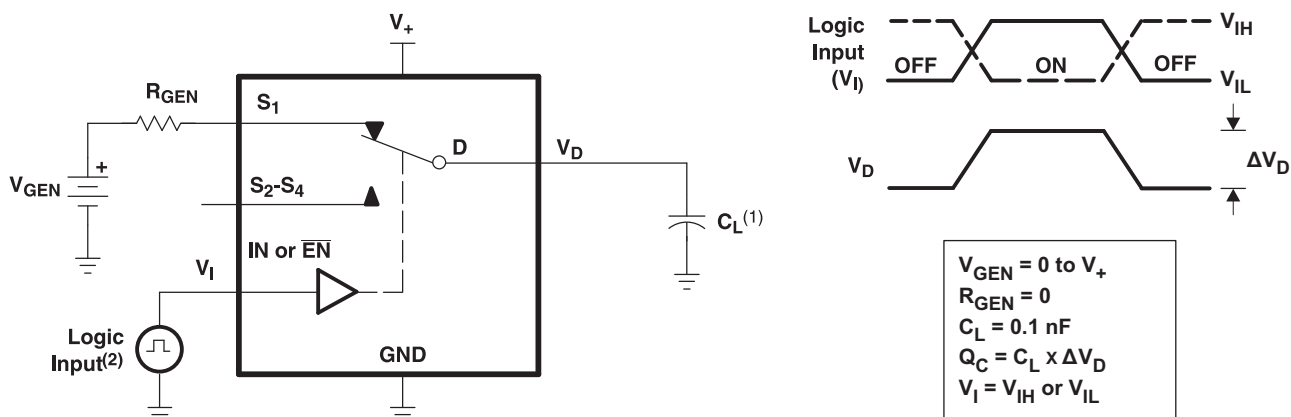


Figure 20. Adjacent Crosstalk (X_{TALK})

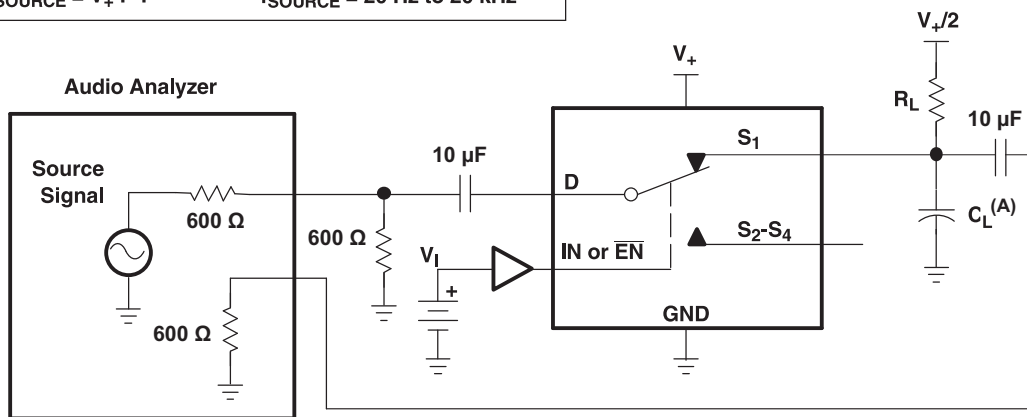
Parameter Measurement Information (continued)



- A. All input pulses are supplied by generators having the following characteristics: PRR ≤ 10 MHz, Z_O = 50 Ω, t_r < 5 ns, t_f < 5 ns.
- B. C_L includes probe and jig capacitance.

Figure 21. Charge Injection (Q_C)

Channel ON: D to S	V _I = V _{IH} or V _{IL}
V _{SOURCE} = V ₊ P-P	f _{SOURCE} = 20 Hz to 20 kHz



- A. C_L includes probe and jig capacitance.

Figure 22. Total Harmonic Distortion (THD)

8 Detailed Description

8.1 Overview

The TS3A5017 is a dual Single-Pole-4-Throw (SP4T) solid-state analog switch. The TS3A5017, like all analog switches, is bidirectional. Each D pin connects to its four respective S pins, with the switch connection dependent on the status of $\overline{\text{EN}}$, IN2, and IN1. See [Table 1](#) for the switch configuration truth table.

8.2 Functional Block Diagram

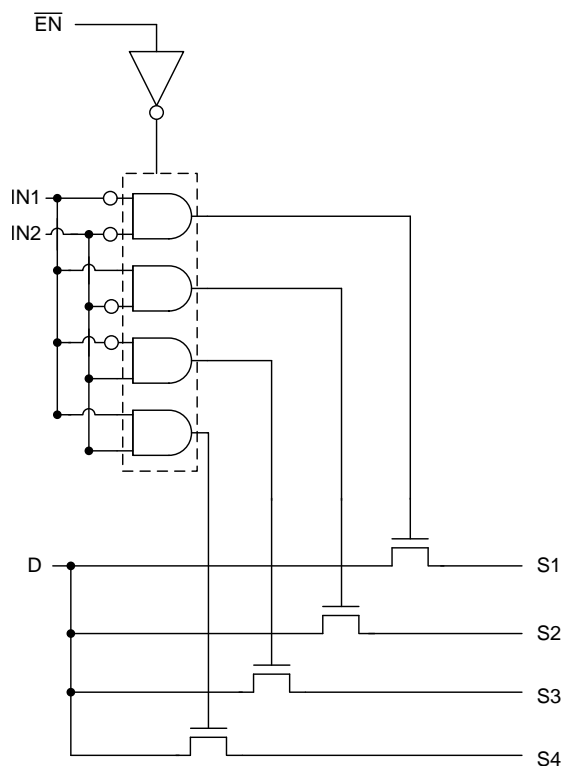


Figure 23. Functional Block Diagram (Each Switch)

8.3 Feature Description

Isolation in powered-down mode allows signals to be present at the inputs while the switch is powered off without causing damage to the device. The low ON-state resistance and low charge injection give the TS3A5017 better performance at higher speeds.

8.4 Device Functional Modes

Table 1. Function Table

$\overline{\text{EN}}$	IN2	IN1	D TO S, S TO D
L	L	L	D = S ₁
L	L	H	D = S ₂
L	H	L	D = S ₃
L	H	H	D = S ₄
H	X	X	OFF

9 Application and Implementation

NOTE

Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

9.1 Application Information

The TS3A5018 can be used in a variety of customer systems. The TS3A5018 can be used anywhere multiple analog or digital signals must be selected to pass across a single line.

9.2 Typical Application

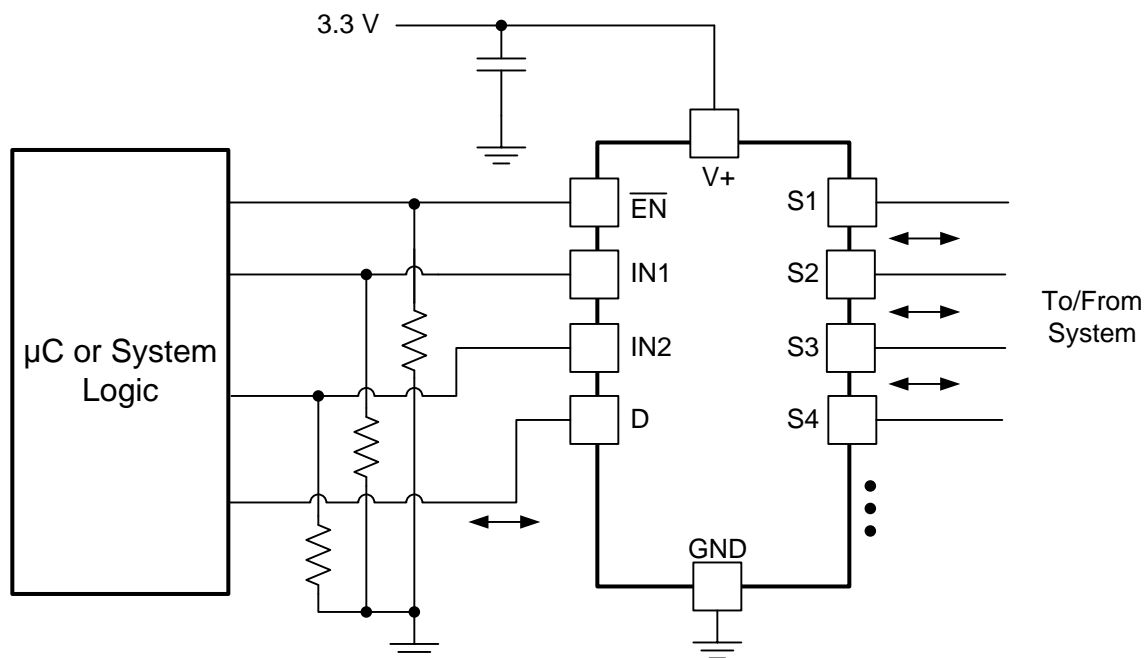


Figure 24. System Schematic for TS3A5017

9.2.1 Design Requirements

In this particular application, V+ was 3.3 V, although V+ is allowed to be any voltage specified in [Recommended Operating Conditions](#). A decoupling capacitor is recommended on the V+ pin. See [Power Supply Recommendations](#) for more details.

9.2.2 Detailed Design Procedure

In this application, $\overline{\text{EN}}$, IN1, and IN2 are, by default, pulled low to GND. Choose these resistor sizes based on the current driving strength of the GPIO, the desired power consumption, and the switching frequency (if applicable). If the GPIO is open-drain, use pullup resistors instead.

Typical Application (continued)

9.2.3 Application Curve

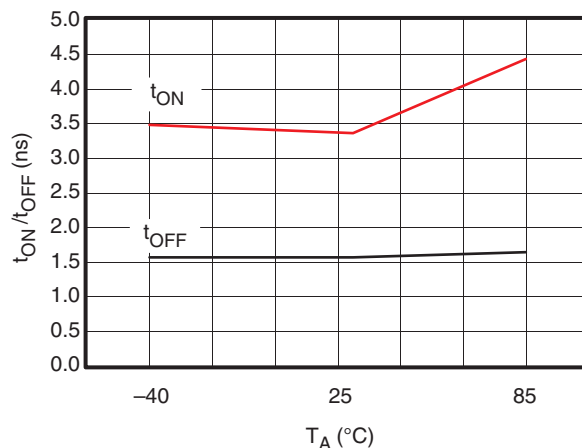


Figure 25. t_{ON} and t_{OFF} vs Temperature (V₊ = 3.3 V)

10 Power Supply Recommendations

The power supply can be any voltage between the minimum and maximum supply voltage rating located in the [Recommended Operating Conditions](#).

Each V_{CC} terminal should have a good bypass capacitor to prevent power disturbance. For devices with a single supply, a 0.1-μF bypass capacitor is recommended. If there are multiple pins labeled V_{CC}, then a 0.01-μF or 0.022-μF capacitor is recommended for each V_{CC} because the V_{CC} pins will be tied together internally. For devices with dual-supply pins operating at different voltages, for example V_{CC} and V_{DD}, a 0.1-μF bypass capacitor is recommended for each supply pin. It is acceptable to parallel multiple bypass capacitors to reject different frequencies of noise. 0.1-μF and 1-μF capacitors are commonly used in parallel. The bypass capacitor should be installed as close to the power terminal as possible for best results.

11 Layout

11.1 Layout Guidelines

Reflections and matching are closely related to loop antenna theory, but different enough to warrant their own discussion. When a PCB trace turns a corner at a 90° angle, a reflection can occur. This is primarily due to the change of width of the trace. At the apex of the turn, the trace width is increased to 1.414 times its width. This upsets the transmission line characteristics, especially the distributed capacitance and self-inductance of the trace — resulting in the reflection. It is a given that not all PCB traces can be straight, and so they will have to turn corners. Below figure shows progressively better techniques of rounding corners. Only the last example maintains constant trace width and minimizes reflections.

Unused switch I/Os, such as NO, NC, and COM, can be left floating or tied to GND. However, the IN1, IN2, and EN pins must be driven high or low. Due to partial transistor turnon when control inputs are at threshold levels, floating control inputs can cause increased I_{CC} or unknown switch selection states. See *Implications of Slow or Floating CMOS Inputs*, [SCBA004](#) for more details.

11.2 Layout Example

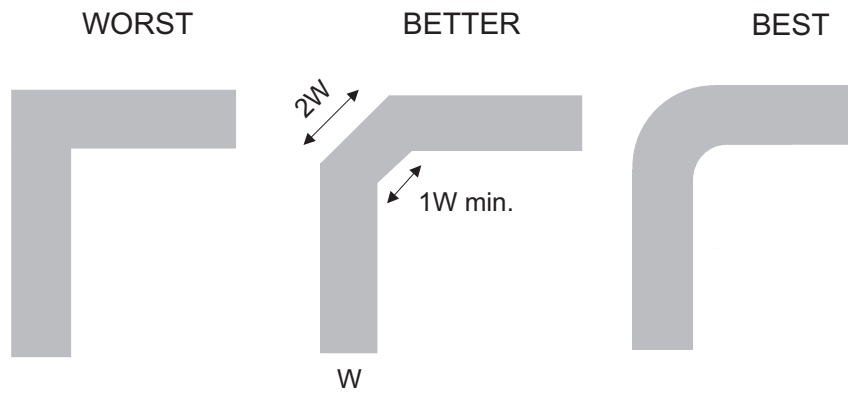


Figure 26. Trace Example

12 デバイスおよびドキュメントのサポート

12.1 デバイス・サポート

12.1.1 デバイスの項目表記

表 2. パラメータの説明

記号	説明
V_{COM}	COM電圧
V_{NC}	NC電圧
V_{NO}	NO電圧
r_{on}	チャンネルがオンのときのCOMとNCポート間、またはCOMとNOポート間の抵抗
Δr_{on}	特定デバイスでのチャンネル間の r_{on} の差
$r_{on(flat)}$	規定の条件の範囲における、チャンネルの r_{on} の最大値と最小値との差
$I_{NC(OFF)}$	対応チャンネル(NCからCOM)がオフ状態のとき、NCポートで測定されるリーク電流
$I_{NC(ON)}$	対応チャンネル(NCからCOM)がオン状態、出力(COM)がオープンのとき、NCポートで測定されるリーク電流
$I_{NO(OFF)}$	対応チャンネル(NOからCOM)がオフ状態のとき、NOポートで測定されるリーク電流
$I_{NO(ON)}$	対応チャンネル(NOからCOM)がオン状態、出力(COM)がオープンのとき、NOポートで測定されるリーク電流
$I_{COM(OFF)}$	対応チャンネル(COMからNCまたはNO)がオフ状態のとき、COMポートで測定されるリーク電流
$I_{COM(ON)}$	対応チャンネル(COMからNCまたはNO)がオン状態、出力(NCまたはNO)がオープン/のとき、COMポートで測定されるリーク電流
V_{IH}	制御入力(IN, \overline{EN})の論理HIGHの最小入力電圧
V_{IL}	制御入力(IN, \overline{EN})の論理LOWの最大入力電圧
V_I	制御入力(IN, \overline{EN})の電圧
I_{IH}, I_{IL}	制御入力(IN, \overline{EN})で測定されるリーク電流
t_{ON}	スイッチのターンオン時間。このパラメータは、規定された条件の範囲で、スイッチがオンになるときのデジタル制御(IN)信号とアナログ出力(NCまたはNO)信号との間の伝搬遅延により測定されます。
t_{OFF}	スイッチのターンオフ時間。このパラメータは、規定された条件の範囲で、スイッチがオフになるときのデジタル制御(IN)信号とアナログ出力(NCまたはNO)信号との間の伝搬遅延により測定されます。
Q_C	電荷注入は、制御(IN)入力からアナログ(NCまたはNO)出力への、望ましくない信号のカップリングの測定値です。この値はクーロン(C)単位で、制御入力のスイッチングによって誘導される合計電荷により測定されます。電荷注入 $Q_C = C_L \times \Delta V_{COM}$ で、 C_L は負荷容量、 ΔV_{COM} はアナログ出力電圧の変化です。
$C_{NC(OFF)}$	対応チャンネル(NCからCOM)がオフのときのNCポートの容量
$C_{NC(ON)}$	対応チャンネル(NCからCOM)がオンのときのNCポートの容量
$C_{NO(OFF)}$	対応チャンネル(NOからCOM)がオフのときのNCポートの容量
$C_{NO(ON)}$	対応チャンネル(NOからCOM)がオンのときのNCポートの容量
$C_{COM(OFF)}$	対応チャンネル(COMからNC)がオフのときのCOMポートの容量
$C_{COM(ON)}$	対応チャンネル(COMからNC)がオンのときのCOMポートの容量
C_I	制御入力(IN, \overline{EN})の容量
O_{ISO}	スイッチのオフ絶縁は、オフ状態のスイッチのインピーダンス測定値です。これは、対応チャンネル(NCからCOM)がオフ状態のとき、特定の周波数についてdB単位で測定されます。
X_{TALK}	クロストークは、オンのチャンネルからオフのチャンネル(NC1からNO1)への、望ましくない信号カップリングの測定値です。隣接クロストークは、オンのチャンネルから隣接するオンのチャンネル(NC1からNC2)への、望ましくない信号カップリングの測定値です。この値は特定の周波数において、dB単位で測定されます。
BW	スイッチの帯域幅。オン状態のチャンネルのゲインがDCゲインより-3dB低くなる周波数です。
THD	全高調波歪は、アナログ・スイッチにより発生する信号の歪みを示します。この値は、2次、3次、およびさらに高次の高調波の二乗平均(RMS)値と、基本波の絶対振幅との比として定義されます。
I_+	制御(IN)ピンが V_+ またはGNDであるときの静的消費電流

12.2 ドキュメントのサポート

12.2.1 関連資料

- 『低速またはフローティングCMOS入力の影響』SCBA004

12.3 商標

All trademarks are the property of their respective owners.

12.4 静電気放電に関する注意事項



これらのデバイスは、限定的なESD(静電破壊)保護機能を内蔵しています。保存時または取り扱い時は、MOSゲートに対する静電破壊を防止するために、リード線同士をショートさせておくか、デバイスを導電フォームに入れる必要があります。

12.5 Glossary

[SLYZ022](#) — *TI Glossary*.

This glossary lists and explains terms, acronyms, and definitions.

13 メカニカル、パッケージ、および注文情報

以降のページには、メカニカル、パッケージ、および注文に関する情報が記載されています。この情報は、そのデバイスについて利用可能な最新のデータです。このデータは予告なく変更されることがあり、ドキュメントが改訂される場合もあります。本データシートのブラウザ版を使用されている場合は、画面左側の説明をご覧ください。

PACKAGING INFORMATION

Orderable Device	Status (1)	Package Type	Package Drawing	Pins	Package Qty	Eco Plan (2)	Lead finish/ Ball material (6)	MSL Peak Temp (3)	Op Temp (°C)	Device Marking (4/5)	Samples
TS3A5017D	LIFEBUY	SOIC	D	16	40	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TS3A5017	
TS3A5017DBQR	ACTIVE	SSOP	DBQ	16	2500	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	YA017	Samples
TS3A5017DGVR	ACTIVE	TVSOP	DGV	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	YA017	Samples
TS3A5017DR	ACTIVE	SOIC	D	16	2500	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	TS3A5017	Samples
TS3A5017PW	LIFEBUY	TSSOP	PW	16	90	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	YA017	
TS3A5017PWR	ACTIVE	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	YA017	Samples
TS3A5017PWRG4	LIFEBUY	TSSOP	PW	16	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	YA017	
TS3A5017RGYR	ACTIVE	VQFN	RGY	16	3000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	YA017	Samples
TS3A5017RGYRG4	LIFEBUY	VQFN	RGY	16	3000	RoHS & Green	NIPDAU	Level-2-260C-1 YEAR	-40 to 85	YA017	
TS3A5017RSVR	ACTIVE	UQFN	RSV	16	3000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 85	ZVL	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) **RoHS:** TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (Cl) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

(3) MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

(4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead finish/Ball material - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer:The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.

OTHER QUALIFIED VERSIONS OF TS3A5017 :

- Automotive : [TS3A5017-Q1](#)

NOTE: Qualified Version Definitions:

- Automotive - Q100 devices qualified for high-reliability automotive applications targeting zero defects

TAPE AND REEL INFORMATION

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE


*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TS3A5017DBQR	SSOP	DBQ	16	2500	330.0	12.5	6.4	5.2	2.1	8.0	12.0	Q1
TS3A5017DGVR	TVSOP	DGV	16	2000	330.0	12.4	6.8	4.0	1.6	8.0	12.0	Q1
TS3A5017DR	SOIC	D	16	2500	330.0	16.4	6.5	10.3	2.1	8.0	16.0	Q1
TS3A5017PWR	TSSOP	PW	16	2000	330.0	12.4	6.9	5.6	1.6	8.0	12.0	Q1
TS3A5017RGYR	VQFN	RGY	16	3000	330.0	12.4	3.8	4.3	1.5	8.0	12.0	Q1
TS3A5017RSVR	UQFN	RSV	16	3000	180.0	12.4	2.1	2.9	0.75	4.0	12.0	Q1

TAPE AND REEL BOX DIMENSIONS

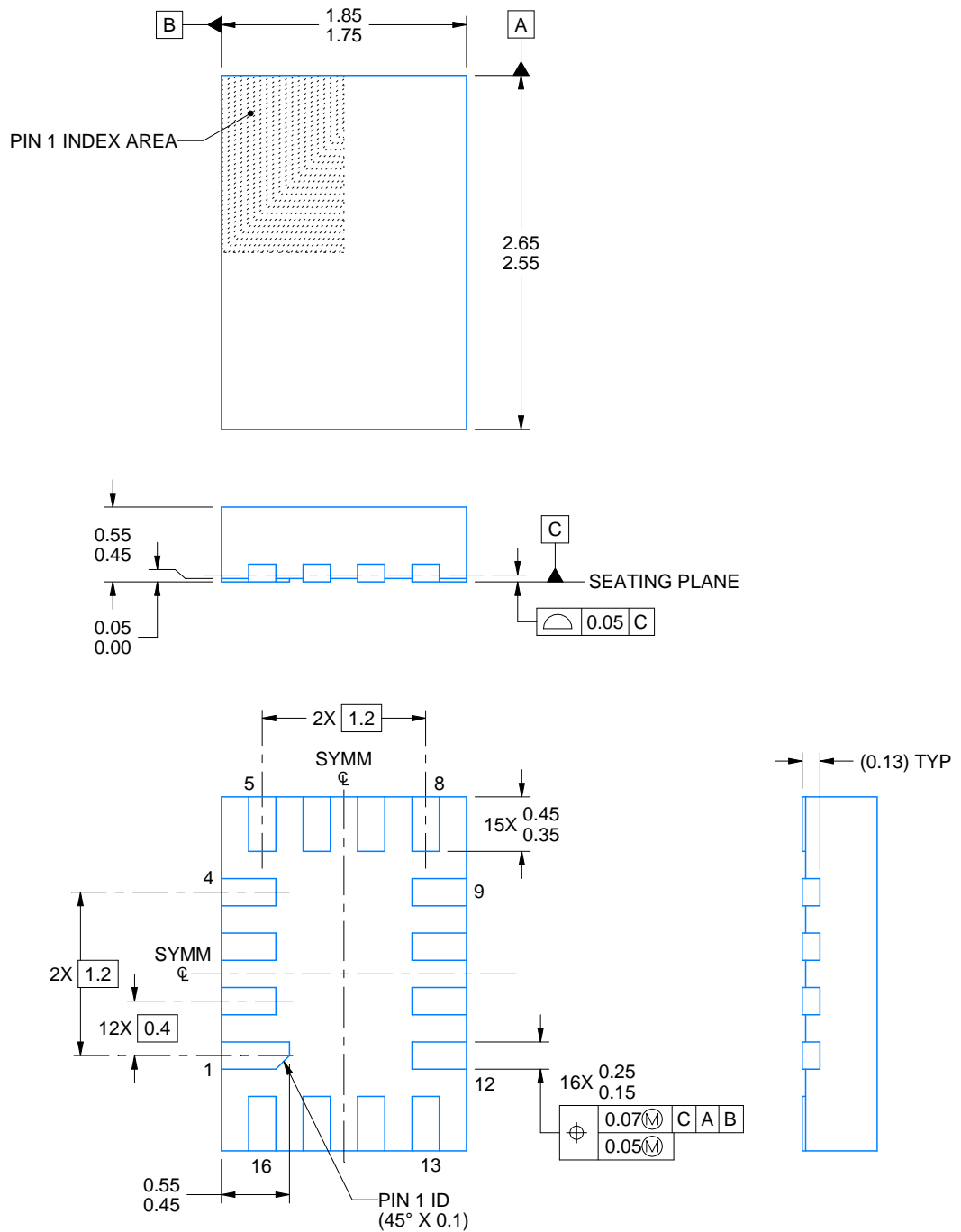
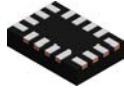

*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TS3A5017DBQR	SSOP	DBQ	16	2500	353.0	353.0	32.0
TS3A5017DGVR	TVSOP	DGV	16	2000	356.0	356.0	35.0
TS3A5017DR	SOIC	D	16	2500	353.0	353.0	32.0
TS3A5017PWR	TSSOP	PW	16	2000	356.0	356.0	35.0
TS3A5017RGYR	VQFN	RGY	16	3000	356.0	356.0	35.0
TS3A5017RSVR	UQFN	RSV	16	3000	200.0	183.0	25.0

TUBE


*All dimensions are nominal

Device	Package Name	Package Type	Pins	SPQ	L (mm)	W (mm)	T (μm)	B (mm)
TS3A5017D	D	SOIC	16	40	507	8	3940	4.32
TS3A5017PW	PW	TSSOP	16	90	530	10.2	3600	3.5



4220314/C 02/2020

NOTES:

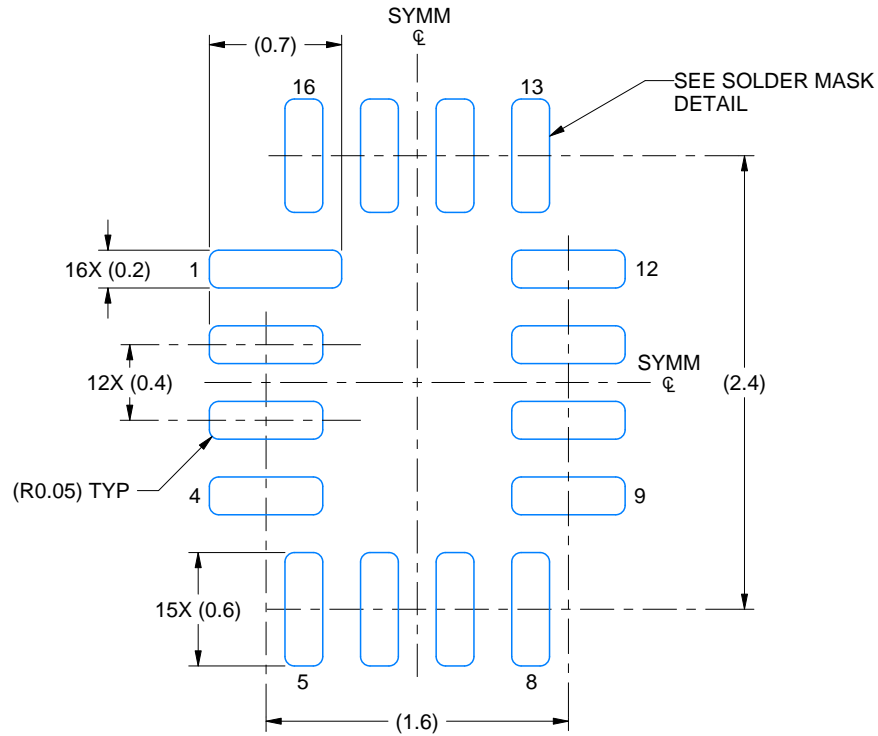
1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.

EXAMPLE BOARD LAYOUT

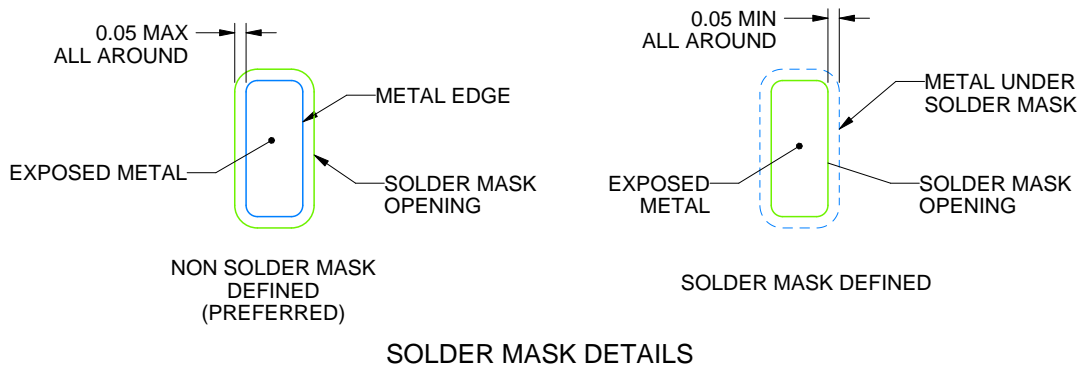
RSV0016A

UQFN - 0.55 mm max height

ULTRA THIN QUAD FLATPACK - NO LEAD



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 25X



4220314/C 02/2020

NOTES: (continued)

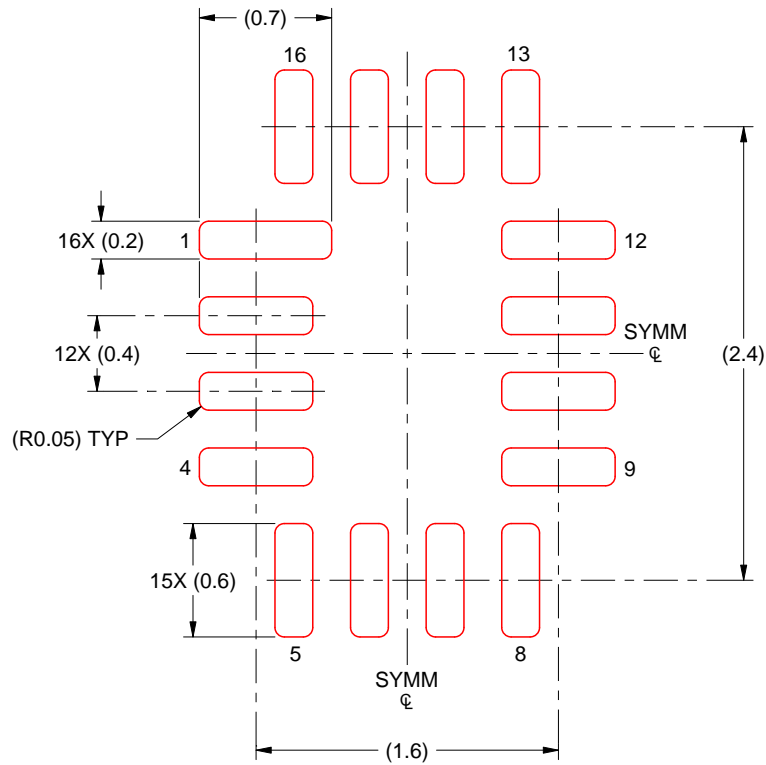
3. For more information, see Texas Instruments literature number SLUA271 (www.ti.com/lit/slua271).

EXAMPLE STENCIL DESIGN

RSV0016A

UQFN - 0.55 mm max height

ULTRA THIN QUAD FLATPACK - NO LEAD



SOLDER PASTE EXAMPLE
BASED ON 0.125 MM THICK STENCIL
SCALE: 25X

4220314/C 02/2020

NOTES: (continued)

4. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.

D (R-PDSO-G16)

PLASTIC SMALL OUTLINE



- NOTES:
- A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice.
 - C. Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.006 (0,15) each side.
 - D. Body width does not include interlead flash. Interlead flash shall not exceed 0.017 (0,43) each side.
 - E. Reference JEDEC MS-012 variation AC.



4220204/A 02/2017

NOTES:

1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 mm per side.
4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
5. Reference JEDEC registration MO-153.

EXAMPLE BOARD LAYOUT

PW0016A

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



LAND PATTERN EXAMPLE
EXPOSED METAL SHOWN
SCALE: 10X



SOLDER MASK DETAILS

4220204/A 02/2017

NOTES: (continued)

- 6. Publication IPC-7351 may have alternate designs.
- 7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

PW0016A

TSSOP - 1.2 mm max height

SMALL OUTLINE PACKAGE



SOLDER PASTE EXAMPLE
BASED ON 0.125 mm THICK STENCIL
SCALE: 10X

4220204/A 02/2017

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

DGV (R-PDSO-G**)

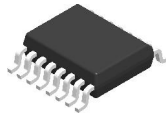
PLASTIC SMALL-OUTLINE

24 PINS SHOWN



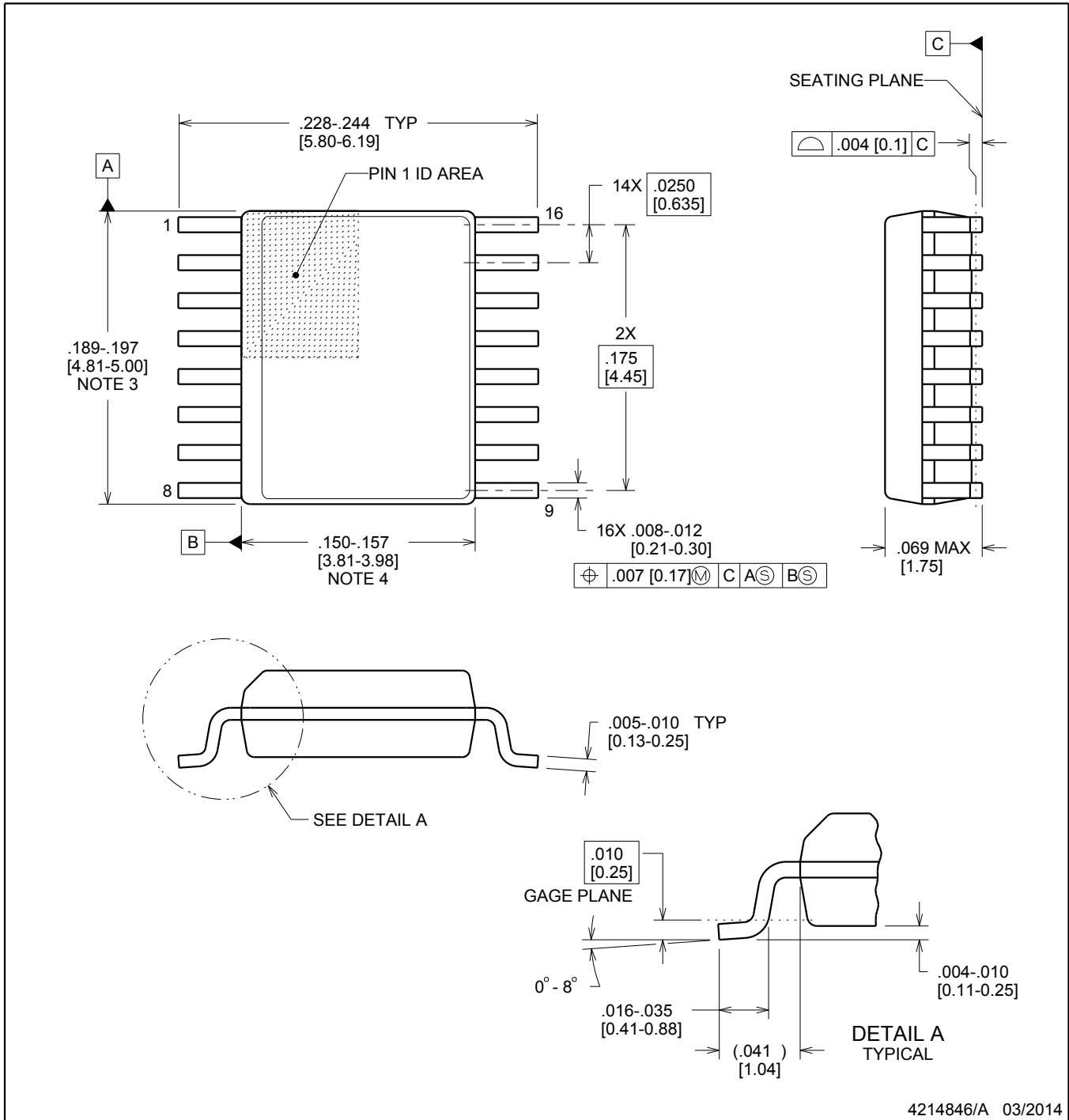
- NOTES: A. All linear dimensions are in millimeters.
 B. This drawing is subject to change without notice.
 C. Body dimensions do not include mold flash or protrusion, not to exceed 0,15 per side.
 D. Falls within JEDEC: 24/48 Pins – MO-153
 14/16/20/56 Pins – MO-194

DBQ0016A



PACKAGE OUTLINE SSOP - 1.75 mm max height

SHRINK SMALL-OUTLINE PACKAGE



NOTES:

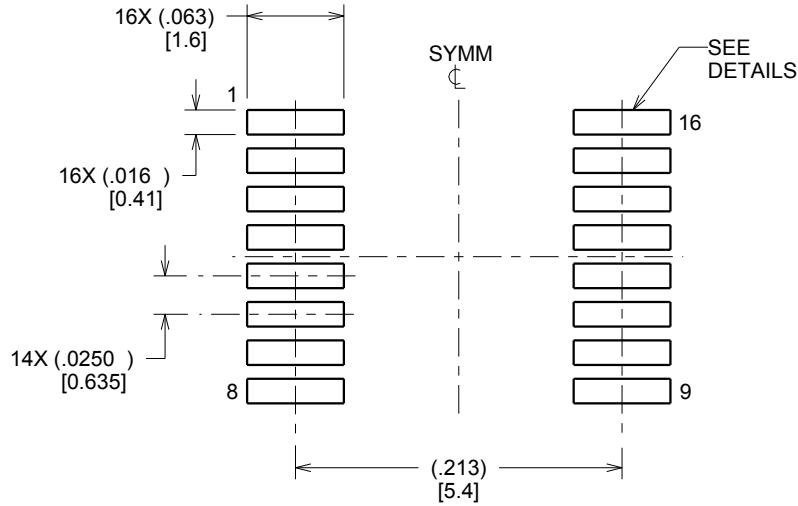
1. Linear dimensions are in inches [millimeters]. Dimensions in parenthesis are for reference only. Controlling dimensions are in inches. Dimensioning and tolerancing per ASME Y14.5M.
2. This drawing is subject to change without notice.
3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed .006 inch, per side.
4. This dimension does not include interlead flash.
5. Reference JEDEC registration MO-137, variation AB.

EXAMPLE BOARD LAYOUT

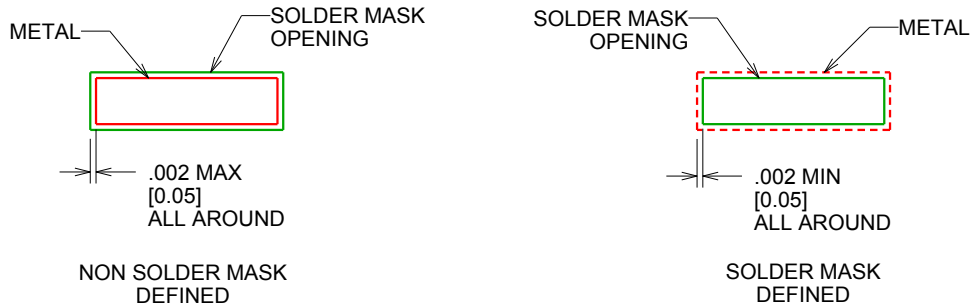
DBQ0016A

SSOP - 1.75 mm max height

SHRINK SMALL-OUTLINE PACKAGE



LAND PATTERN EXAMPLE
SCALE:8X



SOLDER MASK DETAILS

4214846/A 03/2014

NOTES: (continued)

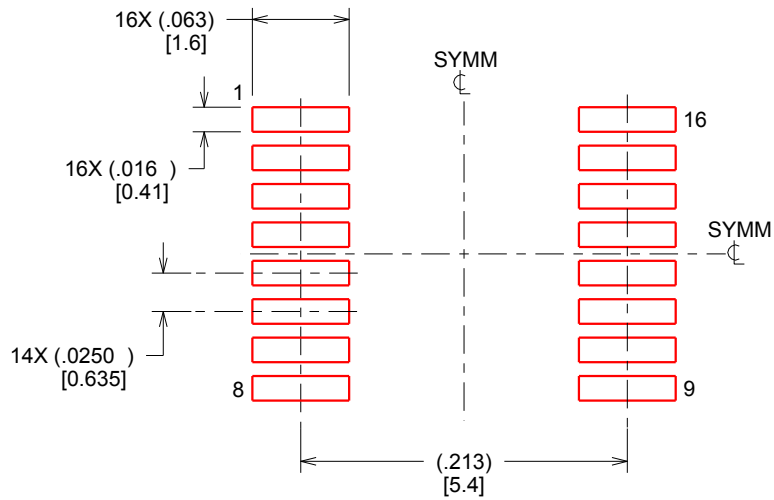
6. Publication IPC-7351 may have alternate designs.
7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.

EXAMPLE STENCIL DESIGN

DBQ0016A

SSOP - 1.75 mm max height

SHRINK SMALL-OUTLINE PACKAGE



SOLDER PASTE EXAMPLE
BASED ON .005 INCH [0.127 MM] THICK STENCIL
SCALE:8X

4214846/A 03/2014

NOTES: (continued)

8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
9. Board assembly site may have different recommendations for stencil design.

RGY (R-PVQFN-N16)

PLASTIC QUAD FLATPACK NO-LEAD



- NOTES:
- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M-1994.
 - B. This drawing is subject to change without notice.
 - C. QFN (Quad Flatpack No-Lead) package configuration.
 - D. The package thermal pad must be soldered to the board for thermal and mechanical performance.
 - E. See the additional figure in the Product Data Sheet for details regarding the exposed thermal pad features and dimensions.
 - F. Pin 1 identifiers are located on both top and bottom of the package and within the zone indicated. The Pin 1 identifiers are either a molded, marked, or metal feature.
 - G. Package complies to JEDEC MO-241 variation BA.

RGY (R-PVQFN-N16)

PLASTIC QUAD FLATPACK NO-LEAD

THERMAL INFORMATION

This package incorporates an exposed thermal pad that is designed to be attached directly to an external heatsink. The thermal pad must be soldered directly to the printed circuit board (PCB). After soldering, the PCB can be used as a heatsink. In addition, through the use of thermal vias, the thermal pad can be attached directly to the appropriate copper plane shown in the electrical schematic for the device, or alternatively, can be attached to a special heatsink structure designed into the PCB. This design optimizes the heat transfer from the integrated circuit (IC).

For information on the Quad Flatpack No-Lead (QFN) package and its advantages, refer to Application Report, QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271. This document is available at www.ti.com.

The exposed thermal pad dimensions for this package are shown in the following illustration.



Bottom View

Exposed Thermal Pad Dimensions

4206353-3/P 03/14

NOTE: All linear dimensions are in millimeters

RGY (R-PVQFN-N16)

PLASTIC QUAD FLATPACK NO-LEAD



4208122-3/P 03/14

- NOTES:
- A. All linear dimensions are in millimeters.
 - B. This drawing is subject to change without notice.
 - C. Publication IPC-7351 is recommended for alternate designs.
 - D. This package is designed to be soldered to a thermal pad on the board. Refer to Application Note, Quad Flat-Pack QFN/SON PCB Attachment, Texas Instruments Literature No. SLUA271, and also the Product Data Sheets for specific thermal information, via requirements, and recommended board layout. These documents are available at www.ti.com <<http://www.ti.com>>.
 - E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC 7525 for stencil design considerations.
 - F. Customers should contact their board fabrication site for minimum solder mask web tolerances between signal pads.

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